NanoSpice SI

PRIMARIUS

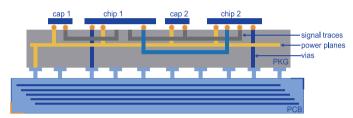
NanoSpice Signal Integrity Solution

Introduction

NanoSpice SI is a fast and precise signal integrity solution dealing with jitter, crosstalk, ringing, ground bounce, and noise problems brought by tighter packaging space and increasing clock frequencies.

With extensive SI models and analysis support, designers can accurately and quickly predict signal integrity issues under such conditions.

Signal Integrity Design on Chip, Package, and PCB Level

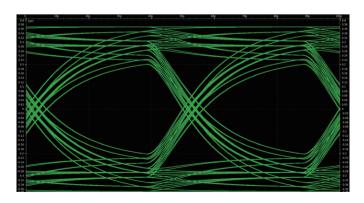


Key Advantages

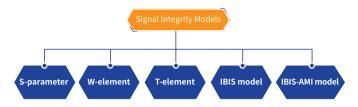
- Extensive model and element support for SI simulation
- Support S-parameters with up to a thousand ports and proven time-domain accuracy
- Superior simulation performance

Applications

- Chip-package co-simulation
- Package-Board-PDN network co-simulation of memory chips
- Noise/Jitter/Crosstalk analysis of high-speed serial interfaces



Typical device models for Signal Integrity



Specifications

- S-parameter analysis
- To extract small-signal S-parameters for a general multi-port network.
- · Statistical eye analysis
- High-speed serial interfaces
- Evaluate eye diagrams and BER quickly and accurately
- AC/Tran analysis
- Transmission line models: W-element and T-element
- S-parameter models
- IBIS files and IBIS-AMI models

Application Examples

| Testcase | Circuit Devices | Reference (s) | NanoSpice SI | Speedup |
|----------|------------------------------------|---------------|--------------|---------|
| case1 | 210-port S-element IBIS element | 79200 | 22042 | 3.59X |
| case2 | 210-port S-element IBIS element | 183600 | 36026 | 5.10X |
| case3 | 210-port S-element IBIS element | 3600 | 513 | 7.02X |
| case4 | 190-port S-element IBIS element | 8108 | 2165 | 3.75X |
| case5 | 179-port S-element | 8953 | 1817 | 4.93X |
| case6 | 728-port S-element IBIS element | 138593 | 45161 | 3.07X |
| case7 | 36-port S-element | 263 | 96 | 2.74X |